

11 th EUropean Failure  
Analysis NETwork EUFANET  
workshop

*Failure Analysis of  
Analog Devices*

October 13, EUFANET Workshop at ESREF 2010

# Workshop program

**9h00: Welcome & Workshop introduction , Philippe Perdu, CNES**

**EUFANET status, Jean-Philippe Roux, Sector Technologies**

**9h10: Technical presentations:**

**Analog IC sample prep, Matthew Lefevre, Digit Concept**

**Variation mapping for analog devices, Philippe Perdu, CNES; Olivier Crepel, Freescale**

**Analogue measurement with emiscope, Frank Zachariasse, NXP**

**Measuring transistors characteristics of sub-32nm devices with SEM-based nano-probing system, Stefan Kleindick, Kleindick**

**Nanoprobing and CAFM for 16 nm elementary structures, Matthew Lefevre, Digit Concept**

**10.20: Round table with the audience**

**10.40: Wrap-up**